

Notice of References Cited		Application/Control No. 10/711,271	Applicant(s)/Patent Under Reexamination EBEL ET AL.	
		Examiner ASHFORD HAYLES	Art Unit 3687	Page 1 of 3

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Notice of References Cited		Application/Control No. 10/711,271	Applicant(s)/Patent Under Reexamination EBEL ET AL.	
		Examiner ASHFORD HAYLES	Art Unit 3687	Page 2 of 3

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		Examiner ASHFORD HAYLES	Art Unit 3687	Page 3 of 3

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